Session Program

27 September 2026 to 2 October 2026

GADEST 2026

Advanced Characterization techniques

GADEST 2026 - San Servolo Island, Venice (Italy)

Thursday 1 October

16:10

Advanced Characterization techniques

Session | **Location:** Auditorium Hall

16:10–16:50

Laboratory Photoluminescence imaging apparatus for identifying crystallographic defects in silicon

Speaker
Isabella Mica

16:50–17:10

A charge decoupling method to infer bulk recombination in high quality silicon wafers

Speaker
Nicholas Grant

17:10–17:30

Beyond Conventional DLTS: Direct Observation of Isotope Shifts in Deep-Level Emission Using Laplace DLTS

Speaker
Vladimir Kolkovsky

17:30–17:50

Defect Profiling in AlInGaP Alloys via MOS Impedance Spectroscopy

Speaker
Paolo La Torraca

17:50–18:10

3D chemical mapping of dopant distribution in epitaxially grown heavily doped Si:P and SiGe:B using atom probe tomography

Speaker
Maryna Dryhailo

18:10